Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/645,249	TAKAHASHI ET AL.	
Examiner	Art Unit	
Justin Krause	3682	

SEARCHED					
Class	Subclass	Date	Examiner		
74	473.3 473.12 473.1 473.19 473.21	5/2/2006	JMK		
	473.35				
	484R 552				
200	61.54				
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		

SEARCH NO (INCLUDING SEARC)
	DATE	EXMR
See East history	5/2/2006	JMK
74 search W Joyce, C Kim		
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